Attorney docket No. BGJ-102



blicant:

Georg Müller

Group: 2829

Application No.:

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Examiner:

Emily Y Chan

Inventor: Georg Müller

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For: Semiconductor Device Testing Apparatus, Semiconductor Device Testing System, and Semiconductor Device Testing Method For Measuring and Trimming the Output Impedance of Driver Devices

DATE OF DEPOSIT: JANUARY 13, 2005

I hereby certify that the correspondence attached hereto is being deposited with the United States Postal Service with sufficient postage as First Class Mail on the date indicated above in an envelope addressed to: Mail Stop Amendment, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

Enclosed:

- 1. Return Receipt Postcard (1);
- 2. Certificate of mailing (1 pg);
- 3. Reply to Restriction Requirement. (8 pgs); and
- 4. Change of Correspondence address to associate Customer Number with this application. $(l \rho s)$

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